

TLP251

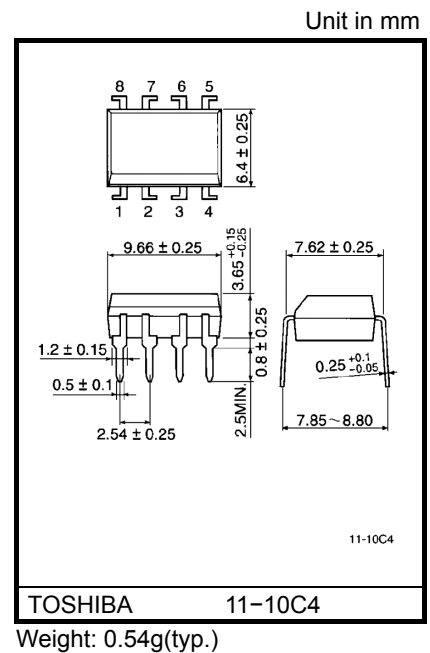
- Inverter For Air Conditioner
- Induction Heating
- Transistor Inverter
- Power MOS FET Gate Drive
- IGBT Gate Drive

The TOSHIBA TLP251 consists of a GaAlAs light emitting diode and a integrated photodetector.
 This unit is 8-lead DIP package.
 TLP251 is suitable for gate driving circuit of IGBT or power MOS FET.
 Especially TLP251 is capable of "direct" gate drive of lower power IGBTs.
 (~15A)

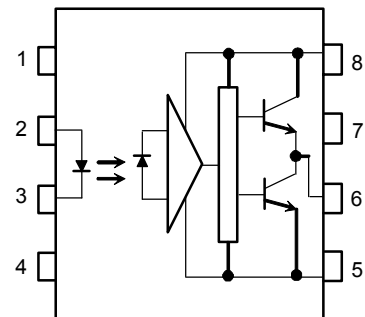
- Input threshold current: $I_F=5\text{mA}(\text{max.})$
 - Supply current (I_{CC}): $11\text{mA}(\text{max.})$
 - Supply voltage (V_{CC}): $10\text{--}35\text{V}$
 - Output current (I_O): $\pm 0.4\text{A}(\text{max.})$
 - Switching time (t_{pLH} / t_{pHL}): $1\mu\text{s}(\text{max.})$
 - Isolation voltage: $2500\text{Vrms}(\text{min.})$
 - UL recognized: UL1577, file no.E67349
 - Option(D4)
 - VDE Approved : DIN EN60747-5-2
 - Maximum Operating Insulation Voltage : 890V_{PK}
 - Highest Permissible Over Voltage : 4000V_{PK}
- (Note):When a EN60747-5-2 approved type is needed,
 Please designate "Option(D4)"

Truth Table

		Tr1	Tr2
		On	Off
Input LED	On	On	Off
	Off	Off	On

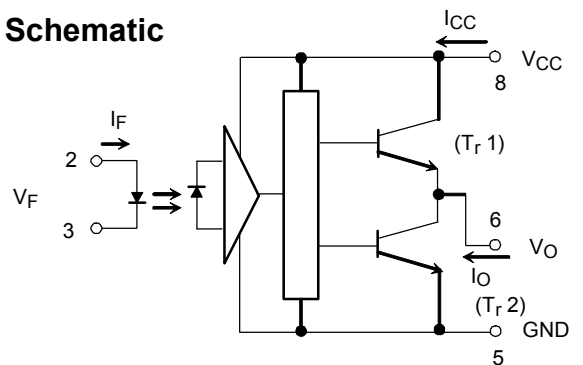


Pin Configuration (top view)



- 1 : N.C. 5 : GND
- 2 : Anode 6 : V_O (Output)
- 3 : Cathode 7 : N.C.
- 4 : N.C. 8 : V_{CC}

Schematic



A 0.1 μF bypass capacitor must be connected between pin 8 and 5(see Note 5).

Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
LED	Forward current	I_F	20	mA	
	Forward current derating (Ta ≥ 70°C)	$\Delta I_F / \Delta T_a$	-0.36	mA / °C	
	Peak transient forward current (Note 1)	I_{FPT}	1	A	
	Reverse voltage	V_R	5	V	
	Junction temperature	T_j	125	°C	
Detector	“H” peak output current (PW ≤ 2.0μs, f ≤ 15kHz) (Note 2)		I_{OPH}	-0.4	A
	“L” peak output current (PW ≤ 2.0μs, f ≤ 15kHz) (Note 2)		I_{OPL}	0.4	A
	Output voltage	(Ta ≤ 70°C)	V_O	35	V
		(Ta = 85°C)		24	
	Supply voltage	(Ta ≤ 70°C)	V_{CC}	35	V
		(Ta = 85°C)		24	
	Output voltage derating (Ta ≥ 70°C)		$\Delta V_O / \Delta T_a$	-0.73	V / °C
	Supply voltage derating (Ta ≥ 70°C)		$\Delta V_{CC} / \Delta T_a$	-0.73	V / °C
	Junction temperature		T_j	125	°C
	Operating frequency (Note 3)		f	25	kHz
Operating temperature range		T_{opr}	-20~85	°C	
Storage temperature range		T_{stg}	-55~125	°C	
Lead soldering temperature(10s)		T_{sol}	260	°C	
Isolation voltage (AC, 1min., R.H.≤ 60%) (Note 4)		BV_S	2500	Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/“Derating Concept and Methods”) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Pulse width $P_W \leq 1\mu s$, 300pps

Note 2: Exponential waveform

Note 3: Exponential waveform, $I_{OPH} \leq -0.25A(\leq 2.0\mu s)$, $I_{OPL} \leq +0.25A(\leq 2.0\mu s)$

Note 4: Device considered a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.

Note 5: A ceramic capacitor(0.1μF)should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching property.The total lead length between capacitor and coupler should not exceed 1cm.

Recommended Operating Conditions

Characteristic	Symbol	Min.	Typ.	Max.	Unit
Input current, on (Note6)	$I_{F(ON)}$	7	8	10	mA
Input voltage, off	$V_{F(OFF)}$	0	—	0.8	V
Supply voltage	V_{CC}	10	—	30 20	V
Peak output current	I_{OPH} / I_{OPL}	—	—	±0.1	A
Operating temperature	T_{opr}	-20	25	70 85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Note 6: Input signal rise time(fall time)<0.5μs.

Electrical Characteristics (Ta = -20~70°C, unless otherwise specified)

Characteristic	Symbol	Test Circuit	Test Condition	Min.	Typ.*	Max.	Unit		
Input forward voltage	V_F	—	$I_F = 10 \text{ mA}$, $T_a = 25^\circ\text{C}$	—	1.6	1.8	V		
Temperature coefficient of forward voltage	$\Delta V_F / \Delta T_a$	—	$I_F = 10 \text{ mA}$	—	-2.0	—	mV / °C		
Input reverse current	I_R	—	$V_R = 5\text{V}$, $T_a = 25^\circ\text{C}$	—	—	10	μA		
Input capacitance	C_T	—	$V = 0$, $f = 1\text{MHz}$, $T_a = 25^\circ\text{C}$	—	45	250	pF		
Output current	“H” level	I_{OPH}	1	$V_{CC}=30\text{V}$ (*1)	$I_F = 10\text{mA}$ $V_{8-6} = 4\text{V}$	-0.1	-0.25	—	A
	“L” level	I_{OPL}	2			$I_F = 0$ $V_{6-5} = 2.5\text{V}$	0.1	0.2	
Output voltage	“H” level	V_{OH}	3	$V_{CC1} = +15\text{V}$, $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$, $I_F = 5\text{mA}$	11	13.2	—	V	
	“L” level	V_{OL}	4	$V_{CC1} = +15\text{V}$, $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$, $V_F = 0.8\text{V}$	—	-14.5	-12.5		
Supply current	“H” level	I_{CCH}	—	$V_{CC} = 30\text{V}$, $I_F = 10\text{mA}$ $T_a = 25^\circ\text{C}$	—	7.5	—	mA	
	“L” level	I_{CCL}	—	$V_{CC} = 30\text{V}$, $I_F = 10\text{mA}$	—	—	11		
				$V_{CC} = 30\text{V}$, $I_F = 0\text{mA}$ $T_a = 25^\circ\text{C}$	—	8	—		
Threshold input current	“Output L → H”	I_{FLH}	—	$V_{CC1} = +15\text{V}$, $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$, $V_O > 0\text{V}$	—	1.2	5	mA	
					“Output H → L”	V_{FHL}	—		$V_{CC1} = +15\text{V}$, $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$, $V_O < 0\text{V}$
Supply voltage	V_{CC}	—	—	10	—	35	V		
Capacitance (input-output)	C_s	—	$V_s = 0$, $f = 1\text{MHz}$ $T_a = 25^\circ\text{C}$	—	1.0	2.0	pF		
Resistance (input-output)	R_s	—	$V_s = 500\text{V}$, $T_a = 25^\circ\text{C}$ $R.H. \leq 60\%$	1×10^{12}	10^{14}	—	Ω		

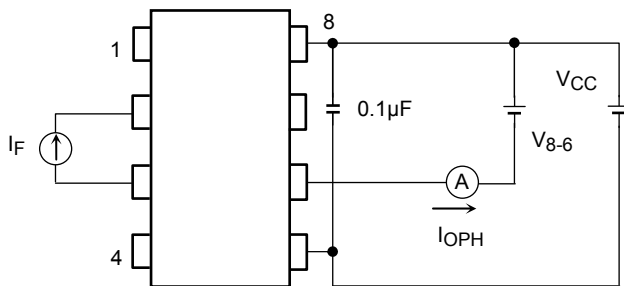
* All typical values are at $T_a=25^\circ\text{C}$ (*1): Duration of I_O time $\leq 50\mu\text{s}$

Switching Characteristics (Ta = -20~70°C, unless otherwise specified)

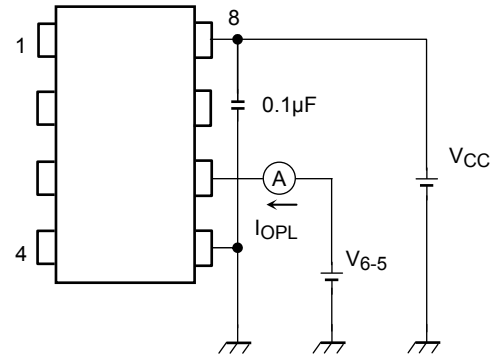
Characteristic		Symbol	Test Circuit	Test Condition	Min.	Typ.*	Max.	Unit		
Propagation delay time	L→H	t_{pLH}	5	$I_F = 8\text{mA}$ $V_{CC1} = +15\text{V}, V_{EE1} = -15\text{V}$ $R_L = 200\ \Omega$	—	0.25	1.0	μs		
	H→L	t_{pHL}			—	0.25	1.0			
Output rise time		t_r			—	—	—		—	—
Output fall time		t_f			—	—	—		—	—
Common mode transient immunity at high level output		C_{MH}	6	$V_{CM} = 600\text{V}, I_F = 8\text{mA},$ $V_{CC} = 30\text{V}, T_a = 25^\circ\text{C}$	-5000	—	—	$\text{V} / \mu\text{s}$		
Common mode transient immunity at low level output		C_{ML}		$V_{CM} = 600\text{V}, I_F = 0\text{mA},$ $V_{CC} = 30\text{V}, T_a = 25^\circ\text{C}$	5000	—	—	$\text{V} / \mu\text{s}$		

*All typical values are at $T_a = 25^\circ\text{C}$

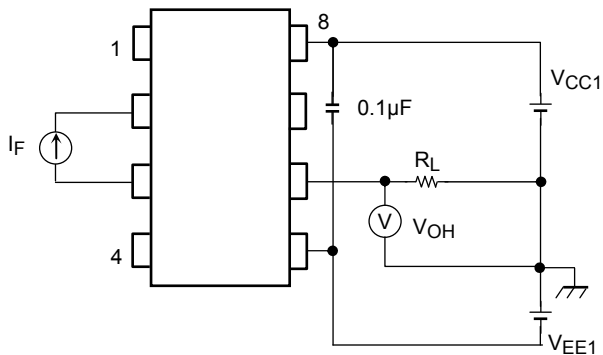
Test Circuit 1 : I_{OPH}



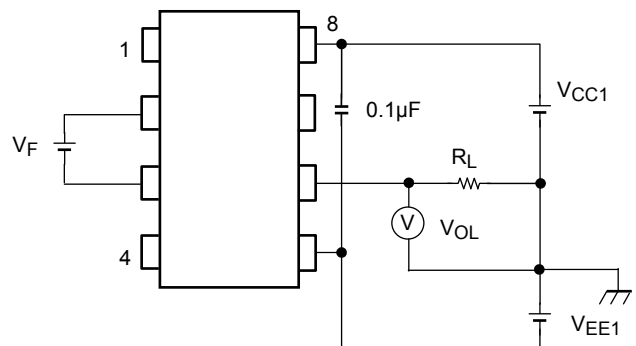
Test Circuit 2 : I_{OPL}



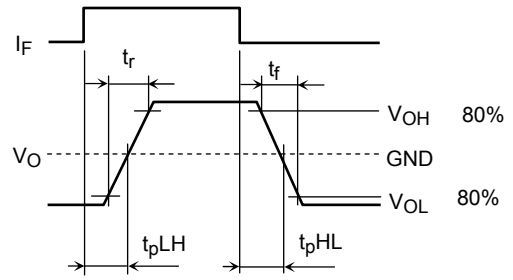
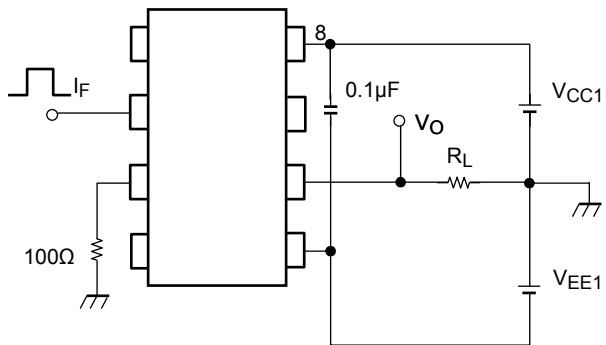
Test Circuit 3 : V_{OH}



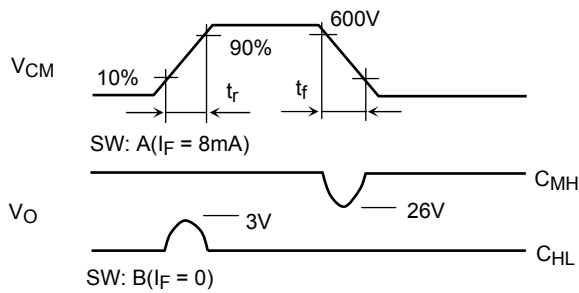
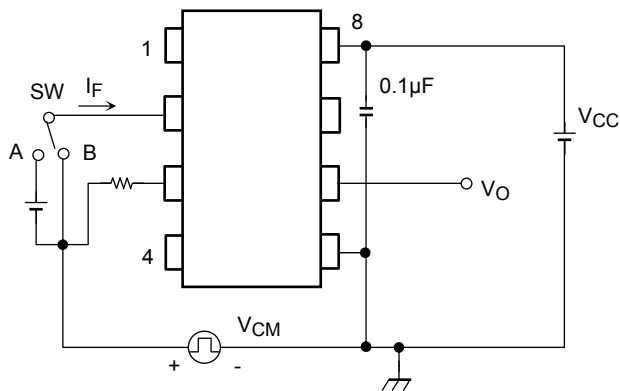
Test Circuit 4 : V_{OL}



Test Circuit 5: t_{pLH} , t_{pHL} , t_r , t_f



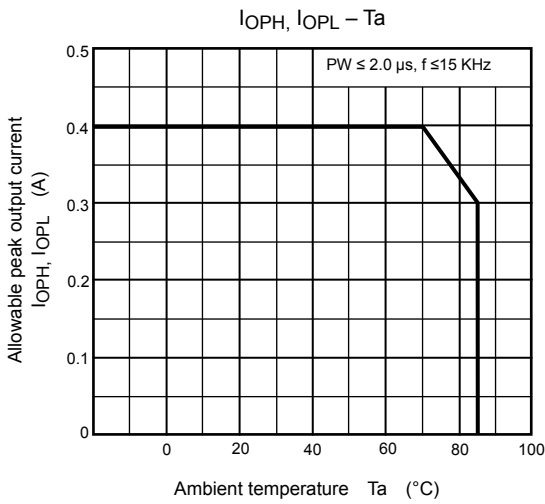
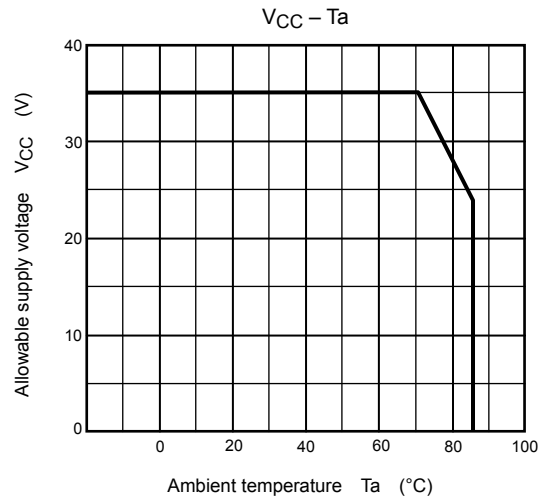
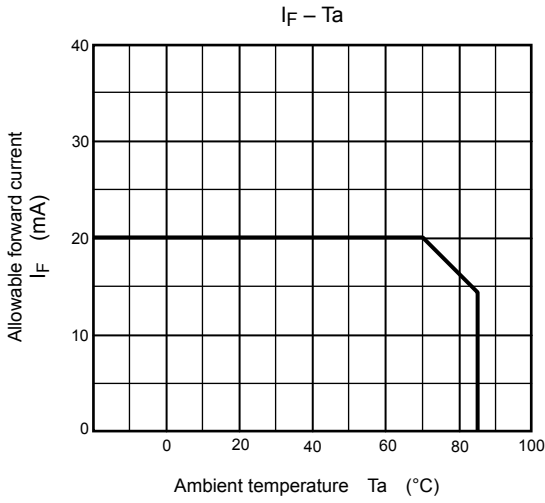
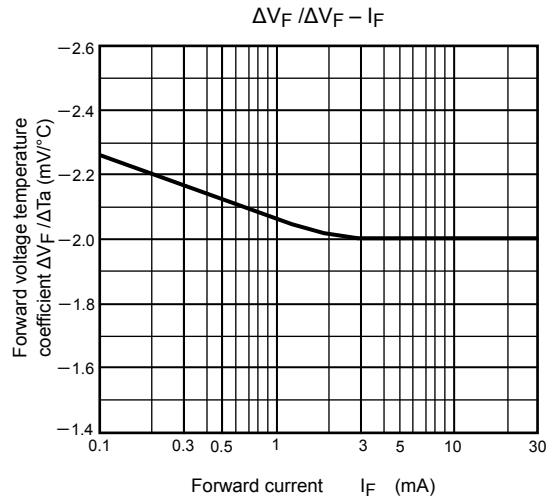
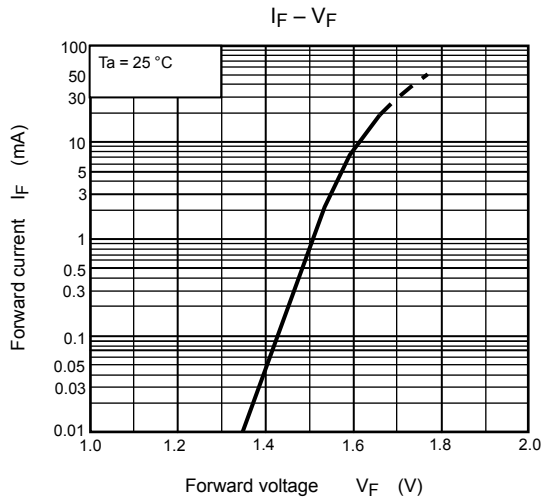
Test Circuit 6: C_{MH} , C_{ML}



$$C_{ML} = \frac{480(V)}{t_r(\mu s)}$$

$$C_{MH} = \frac{480(V)}{t_f(\mu s)}$$

C_{ML} (C_{MH}) is the maximum rate of rise (fall) of the common mode voltage that can be sustained with the output voltage in the low (high) state.



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